

<p style="text-align: center;"><b>Search Notes</b></p> <div style="text-align: center;">  </div>	<p style="text-align: center;"><b>Application/Control No.</b></p> <p>10/549,254</p>	<p style="text-align: center;"><b>Applicant(s)/Patent under Reexamination</b></p> <p>KAPAAN ET AL.</p>	
	<p style="text-align: center;"><b>Examiner</b></p> <p>David D. Le</p>	<p style="text-align: center;"><b>Art Unit</b></p> <p>3681</p>	
<b>SEARCHED</b>		<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>	
Class	Subclass	Date	Examiner
475	149, 151	5/21/2008	DDL
475	152, 153	5/21/2008	DDL
475	343, 344	5/21/2008	DDL
192	21, 51	5/21/2008	DDL
192	53.34	5/21/2008	DDL
192	84.6	5/21/2008	DDL
192	94	5/21/2008	DDL
<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner